

Notice of References Cited	Application/Control No. 10/575,187		Applicant(s)/Patent Under Reexamination FUTAGAWA ET AL.	
	Examiner Keath T. Chen		Art Unit 1792	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2001/0000476	04-2001	Xia et al.	427/255.27
*	C	US-6,204,174	03-2001	Glew et al.	438/680
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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